## 12Pt300B or 12Pt300A

The 12Pt300B has a higher spring constant than the 12Pt400B. It is typically used for contact AFM imaging, when a higher resonance frequency is desired. These probes are ideal for C-AFM, SCM, SMM, SMIM, and PFM applications.

- Tip shank length: 80 μm (± 25%)
- Cantilever length: 300 µm (± 15%)
- Cantilever width: 60 µm (± 15%)
- Spring constant: 0.8 N/m (± 40%)
- Frequency: 9 kHz (± 30%)
- Standard tip radii below 20 nm for \$90 each
- Tip radii below 10 nm on request for \$112 each 12Pt300B-10
- Non standard probe tips and cantilevers upon request